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PTO/SB/08A (08-03)

Approved for use through 07/31/2006. OMB 0651-0031

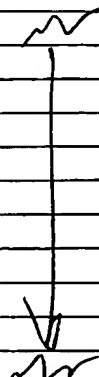
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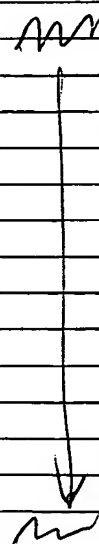
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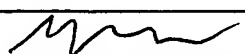
Substitute for form 1449/PTO			<b>Complete if Known</b>		
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(Use as many sheets as necessary)</i>			Application Number		
			Filing Date		
			First Named Inventor	<b>Hoshang Subawalla, et al.</b>	
			Art Unit		
			Examiner Name		
Sheet	<b>1</b>	Of	<b>3</b>	Attorney Docket Number	<b>06413P USA</b>

U. S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
		US- 2002/0112747 A1	8/22/2002	J. P. DeYoung, et al.	
		US- 2002/0088477 A1	7/11/2002	J. M. Cotte, et al.	
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Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				
		EP 0 836 895 A2	4/22/1998	Europe		✓
		WO 00/16264	3/23/2000	World		✓
		WO 00/26421	5/11/2000	World		✓
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		WO 01/87505	11/22/2001	World		✓
		WO 02/11191	2/7/2002	World		✓
		WO 02/15251 A1	2/21/2002	World		✓
		WO 02/66176	8/29/2002	World		✓
		WO 84/02291	6/21/1984	World		✓
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		WO 99/49998	10/7/1999	World		✓
		WO 99/61177	12/2/1999	World		✓

Examiner Signature		Date Considered	9/19/05
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			Art Unit		
			Examiner Name		
Sheet	<b>3</b>	Of	<b>3</b>	Attorney Docket Number	<b>06413P USA</b>

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
<i>W</i>		K. Jackson, et al., "Microemulsions in Supercritical Hydrochlorofluorocarbons," Langmuir 12(22), pp. 5289-5295 (1996).	
<i>W</i>		M. A. Biberger, et al., "Photoresist and Photoresist Residue Removal with Supercritical CO <sub>2</sub> - A Novel Approach to Cleaning Wafers," Semiconductor Fabtech, 12 <sup>th</sup> Ed., pp. 239-243.	
<i>W</i>		D. Beery, et al., "Post Etch Residue Removal: Novel Dry Clean Technology Using Densified Fluid Cleaning (DFC)," IITC 99, pp. 140-142.	
<i>W</i>		J. Liu, et al., "Investigation of Nonionic Surfactant Dynol-604 Based Reverse Microemulsions Formed in Supercritical Carbon Dioxide," Langmuir 17, pp. 8040-8043 (2001).	
<i>W</i>		K. Jackson, et al., "Surfactants and Microemulsions in Supercritical Fluids," Supercritical Fluid Cleaning, pp. 87- 120.	
<i>W</i>		R. A. Bowling, et al., "Future Challenges for Cleaning in Advanced Microelectronics," Texas Instruments slides.	
<i>W</i>		H. J. Martinez, et al., "SCCO <sub>2</sub> - Is it an Enabling Technology for the 90nm Node and Beyond?" International SeMatech slides (2002).	
<i>W</i>		S. Pawat, "Novel Wafer Clean Technologies," International SeMatech slides (2001).	
<i>W</i>		T. Hurd, et al., "scCO <sub>2</sub> Cleaning Applications in Porous ULK Processing," Texas Instruments slides.	
<i>W</i>		G. L. Weibel, et al., "Supercritical CO <sub>2</sub> in Microelectronics Processing," Cornell University slides.	
<i>W</i>		J. B. Rubin, et al., "Precision Cleaning of Semiconductor Surfaces Using Carbon Dioxide-Based Fluids," Clarkson University, pp. 1-26.	
<i>W</i>		G. Weibel, "Supercritical CO <sub>2</sub> for Semiconductor Applications," Semiconductor Equipment and Materials International (2001).	
<i>W</i>		J. Malloy, et al., "GC Analysis of Solvent Wash Samples," Air Products and Chemicals, Inc. (2003).	
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<i>W</i>		Enokida, Y. et al., "Ultrasound-Enhanced Dissolution of UO <sub>2</sub> in Supercritical CO <sub>2</sub> Containing a CO <sub>2</sub> -Phylic Complexant of Tri-n-Butylphosphate and Nitric Acid", Industrial & Engineering Chemistry Research, (2002), 41 (9), pp.2282-2286	


Examiner Signature	<i>[Signature]</i>	Date Considered	<i>9-19-05</i>
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
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




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			Application Number	10/737,203	
			Filing Date	December 16, 2003	
			First Named Inventor	Hoshang Subawalla, et al.	
			Art Unit	1765	
			Examiner Name		
Sheet	1	of	1	Attorney Docket Number	06413P USA

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		Number-Kind Code <sup>2</sup> (if known)			
		US- 6,589,355 B1	07-08-2003	Thomas, et al.	
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		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				
		EP 0 830 890	03-25-1998	Air Products and Chemicals, Inc.		✓
		WO 03/057811	07-17-2003	Advanced Technology Materials, Inc.		✓
		EP 1 050 577	11-08-2000	Air Products and Chemicals, Inc.		✓
		EP 1 115 035	07-11-2001	Air Products and Chemicals, Inc.		✓
		EP 1 402 963	03-31-2004	Air Products and Chemicals, Inc.		✓

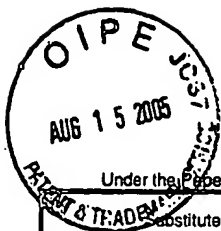
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AL		WO 2005/038898 A1	04-28-2005	EKC Technology, Inc.		

Examiner Signature		Date Considered	9-19-05
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